# CY7C1019B

# 128K x 8 Static RAM

## Features

- **High speed**
  - **— $t_{AA}$ = 12 ns**
- **CMOS for optimum speed/power**
- **Center power/ground pinout**
- **Automatic power-down when deselected**
- **Easy memory expansion with $\overline{CE}$ and $\overline{OE}$ options**
- **Functionally equivalent to CY7C1019**
- **Available in Pb-free and non Pb-free 32-pin TSOP II, non Pb-free 400-mil-wide SOJ packages.**

## Functional Description

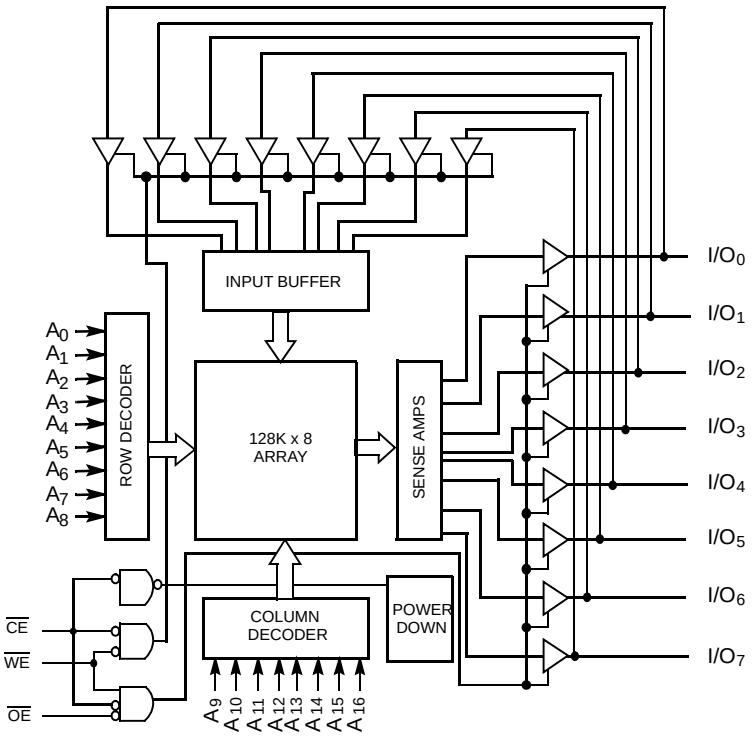
The CY7C1019B is a high-performance CMOS static RAM organized as 131,072 words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable ($\overline{CE}$), an active LOW Output Enable ($\overline{OE}$), and tri-state drivers. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

Writing to the device is accomplished by taking Chip Enable ($\overline{CE}$) and Write Enable ($\overline{WE}$) inputs LOW. Data on the eight I/O pins ($I/O_0$ through $I/O_7$) is then written into the location specified on the address pins ($A_0$ through $A_{16}$).

Reading from the device is accomplished by taking Chip Enable ($\overline{CE}$) and Output Enable ($\overline{OE}$) LOW while forcing Write Enable ($\overline{WE}$) HIGH. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.

The eight input/output pins ($I/O_0$ through $I/O_7$) are placed in a high-impedance state when the device is deselected ($\overline{CE}$ HIGH), the outputs are disabled ($\overline{OE}$ HIGH), or during a write operation ($\overline{CE}$ LOW, and $\overline{WE}$ LOW).

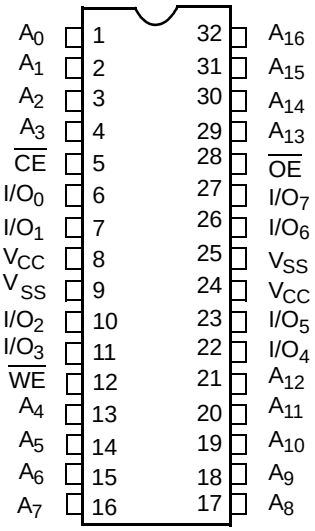
## Logic Block Diagram




## Pin Configurations

**SOJ /TSOPII**

**Top View**




## Selection Guide

| | -12 | -15 | Unit |
|---|---|---|---|
| Maximum Access Time | 12 | 15 | ns |
| Maximum Operating Current | 140 | 130 | mA |
| Maximum Standby Current | 10 | 10 | mA |

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature .....–65°C to +150°C

Ambient Temperature with Power Applied.....–55°C to +125°C

Supply Voltage on $V_{CC}$ to Relative GND[1] .... –0.5V to +7.0V

DC Voltage Applied to Outputs in High Z State[1] .....–0.5V to $V_{CC}$ + 0.5V

DC Input Voltage[1].....–0.5V to $V_{CC}$ + 0.5V

Current into Outputs (LOW)..... 20 mA

Static Discharge Voltage.....>2001V (per MIL-STD-883, Method 3015)

Latch-Up Current .....>200 mA

## Operating Range

| Range | Ambient Temperature[2] | $V_{CC}$ |
|---|---|---|
| Commercial | 0°C to +70°C | 5V ± 10% |

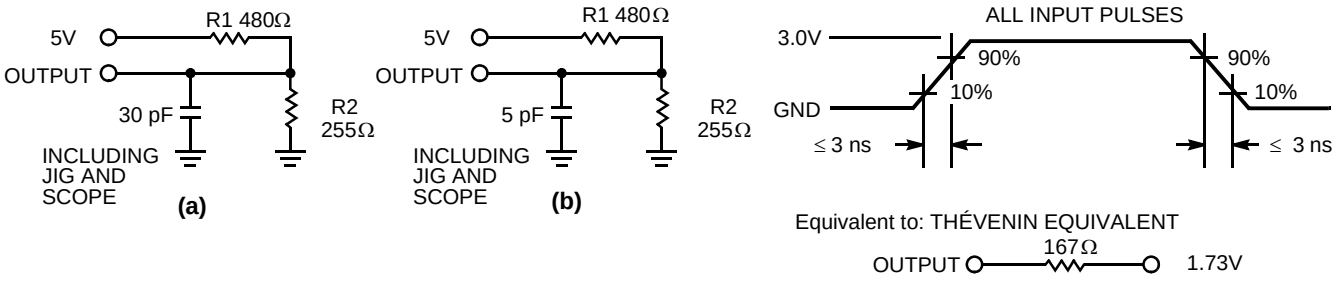
## Electrical Characteristics Over the Operating Range

| Parameter | Description | Test Conditions | -12 | | -15 | | Unit |
|---|---|---|---|---|---|---|---|
| | | | Min. | Max. | Min. | Max. | |
| $V_{OH}$ | Output HIGH Voltage | $V_{CC}$ = Min., $I_{OH}$ = – 4.0 mA | 2.4 | | 2.4 | | V |
| $V_{OL}$ | Output LOW Voltage | $V_{CC}$ = Min., $I_{OL}$ = 8.0 mA | | 0.4 | | 0.4 | V |
| $V_{IH}$ | Input HIGH Voltage | | 2.2 | $V_{CC}$ + 0.3 | 2.2 | $V_{CC}$ + 0.3 | V |
| $V_{IL}$ | Input LOW Voltage[1] | | –0.3 | 0.8 | –0.3 | 0.8 | V |
| $I_{IX}$ | Input Leakage Current | GND ≤ $V_I$ ≤ $V_{CC}$ | –1 | +1 | –1 | +1 | µA |
| $I_{OZ}$ | Output Leakage Current | GND ≤ $V_I$ ≤ $V_{CC}$, Output Disabled | –5 | +5 | –5 | +5 | µA |
| $I_{CC}$ | $V_{CC}$ Operating Supply Current | $V_{CC}$ = Max., $I_{OUT}$ = 0 mA, f = $f_{MAX}$ = $1/t_{RC}$ | | 140 | | 130 | mA |
| $I_{SB1}$ | Automatic CE Power- Down Current —TTL Inputs | Max. $V_{CC}$, $\overline{CE}$ ≥ $V_{IH}$ $V_{IN}$ ≥ $V_{IH}$ or $V_{IN}$ ≤ $V_{IL}$, f = $f_{MAX}$ | | 40 | | 40 | mA |
| $I_{SB2}$ | Automatic CE Power-Down Current —CMOS Inputs | Max. $V_{CC}$, $\overline{CE}$ ≥ $V_{CC}$ – 0.3V, $V_{IN}$ ≥ $V_{CC}$ – 0.3V, or $V_{IN}$ ≤ 0.3V, f = 0 | | 10 | | 10 | mA |

## Capacitance[3]

| Parameter | Description | Test Conditions | Max. | Unit |
|---|---|---|---|---|
| $C_{IN}$ | Input Capacitance | $T_A$ = 25°C, f = 1 MHz, $V_{CC}$ = 5.0V | 6 | pF |
| $C_{OUT}$ | Output Capacitance | | 8 | pF |

## AC Test Loads and Waveforms



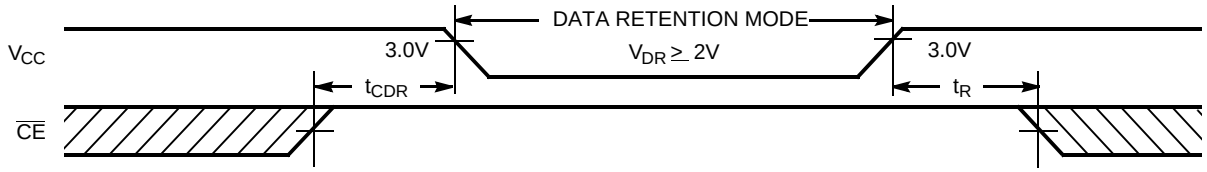

**Notes:**
1. $V_{IL}$ (min.) = –2.0V for pulse durations of less than 20 ns.
2. $T_A$ is the "Instant On" case temperature.
3. Tested initially and after any design or process changes that may affect these parameters.

## Switching Characteristics[4] Over the Operating Range

| Parameter | Description | -12 | | -15 | | Unit |
|---|---|---|---|---|---|---|
| | | Min. | Max. | Min. | Max. | |
| **Read Cycle** | | | | | | |
| $t_{RC}$ | Read Cycle Time | 12 | | 15 | | ns |
| $t_{AA}$ | Address to Data Valid | | 12 | | 15 | ns |
| $t_{OHA}$ | Data Hold from Address Change | 3 | | 3 | | ns |
| $t_{ACE}$ | $\overline{CE}$ LOW to Data Valid | | 12 | | 15 | ns |
| $t_{DOE}$ | $\overline{OE}$ LOW to Data Valid | | 6 | | 7 | ns |
| $t_{LZOE}$ | $\overline{OE}$ LOW to Low Z | 0 | | 0 | | ns |
| $t_{HZOE}$ | $\overline{OE}$ HIGH to High Z[5, 6] | | 6 | | 7 | ns |
| $t_{LZCE}$ | $\overline{CE}$ LOW to Low Z[6] | 3 | | 3 | | ns |
| $t_{HZCE}$ | $\overline{CE}$ HIGH to High Z[5, 6] | | 6 | | 7 | ns |
| $t_{PU}$ | $\overline{CE}$ LOW to Power-Up | 0 | | 0 | | ns |
| $t_{PD}$ | $\overline{CE}$ HIGH to Power-Down | | 12 | | 15 | ns |
| **Write Cycle**[7, 8] | | | | | | |
| $t_{WC}$ | Write Cycle Time | 12 | | 15 | | ns |
| $t_{SCE}$ | $\overline{CE}$ LOW to Write End | 9 | | 10 | | ns |
| $t_{AW}$ | Address Set-Up to Write End | 8 | | 10 | | ns |
| $t_{HA}$ | Address Hold from Write End | 0 | | 0 | | ns |
| $t_{SA}$ | Address Set-Up to Write Start | 0 | | 0 | | ns |
| $t_{PWE}$ | $\overline{WE}$ Pulse Width | 8 | | 10 | | ns |
| $t_{SD}$ | Data Set-Up to Write End | 6 | | 8 | | ns |
| $t_{HD}$ | Data Hold from Write End | 0 | | 0 | | ns |
| $t_{LZWE}$ | $\overline{WE}$ HIGH to Low Z[6] | 3 | | 3 | | ns |
| $t_{HZWE}$ | $\overline{WE}$ LOW to High Z[5, 6] | | 6 | | 7 | ns |

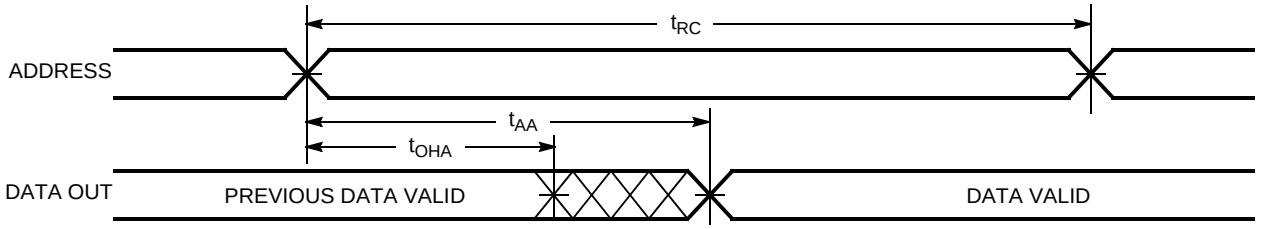
**Notes:**
4. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified $I_{OL}/I_{OH}$ and 30-pF load capacitance.
5. $t_{HZOE}$, $t_{HZCE}$, and $t_{HZWE}$ are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
6. At any given temperature and voltage condition, $t_{HZCE}$ is less than $t_{LZCE}$, $t_{HZOE}$ is less than $t_{LZOE}$, and $t_{HZWE}$ is less than $t_{LZWE}$ for any given device.
7. The internal write time of the memory is defined by the overlap of $\overline{CE}$ LOW and $\overline{WE}$ LOW. $\overline{CE}$ and $\overline{WE}$ must be LOW to initiate a write, and the transition of any of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.
8. The minimum write cycle time for Write Cycle no. 3 ($\overline{WE}$ controlled, $\overline{OE}$ LOW) is the sum of $t_{HZWE}$ and $t_{SD}$.

## Data Retention Waveform

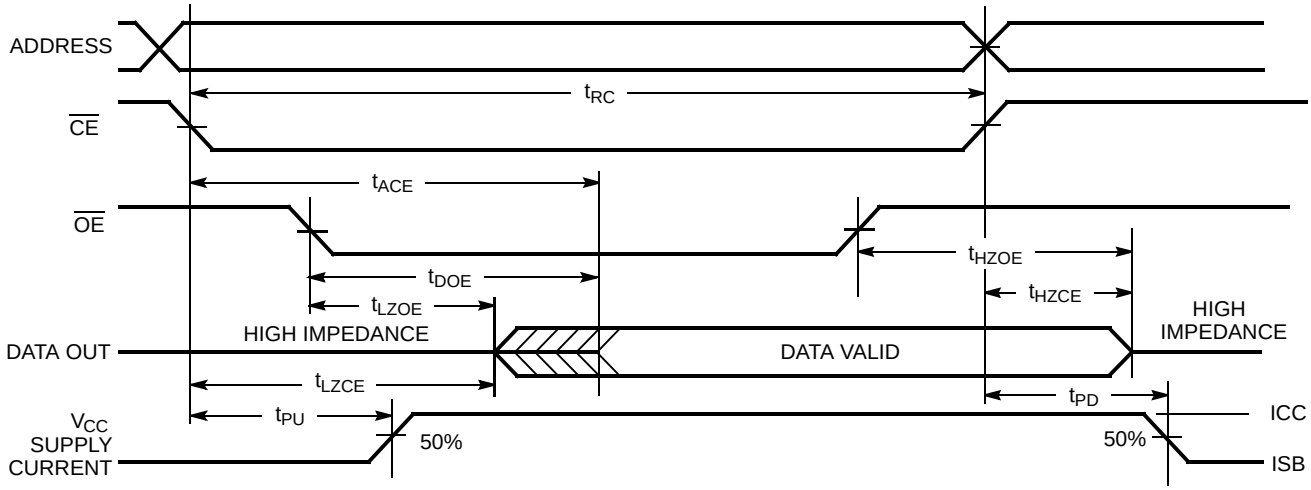



## Switching Waveforms

### Read Cycle No. 1[9, 10]



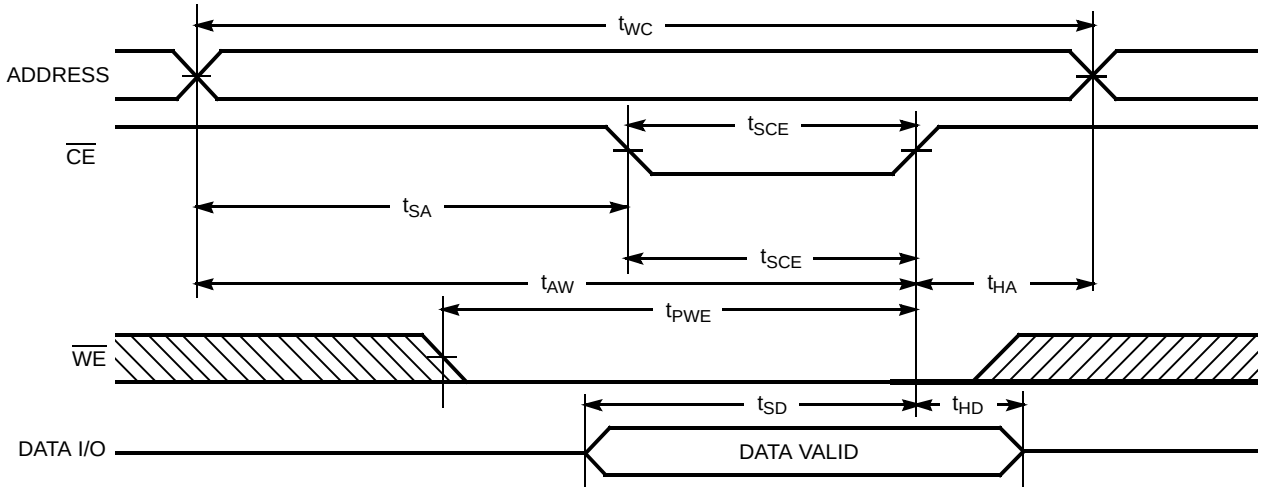

### Read Cycle No. 2 ($\overline{OE}$ Controlled)[10, 11]



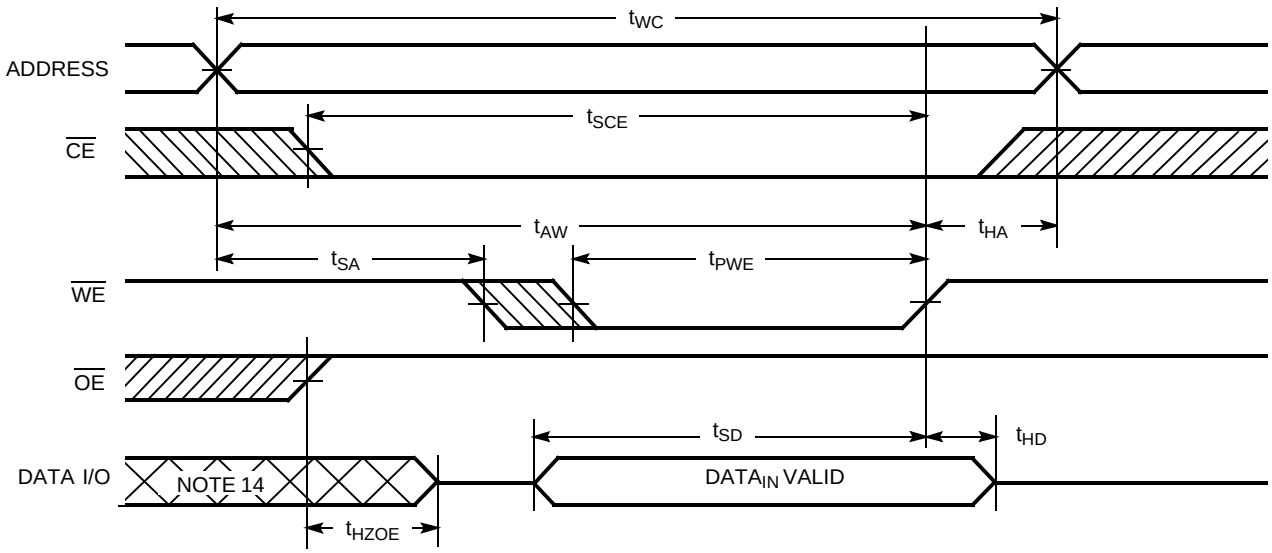

**Notes:**
9. Device is continuously selected. $\overline{OE}$, $\overline{CE}$ = $V_{IL}$.
10. $\overline{WE}$ is HIGH for read cycle.
11. Address valid prior to or coincident with $\overline{CE}$ transition LOW.

## Switching Waveforms (continued)

### Write Cycle No. 1 ($\overline{CE}$ Controlled)[12, 13]



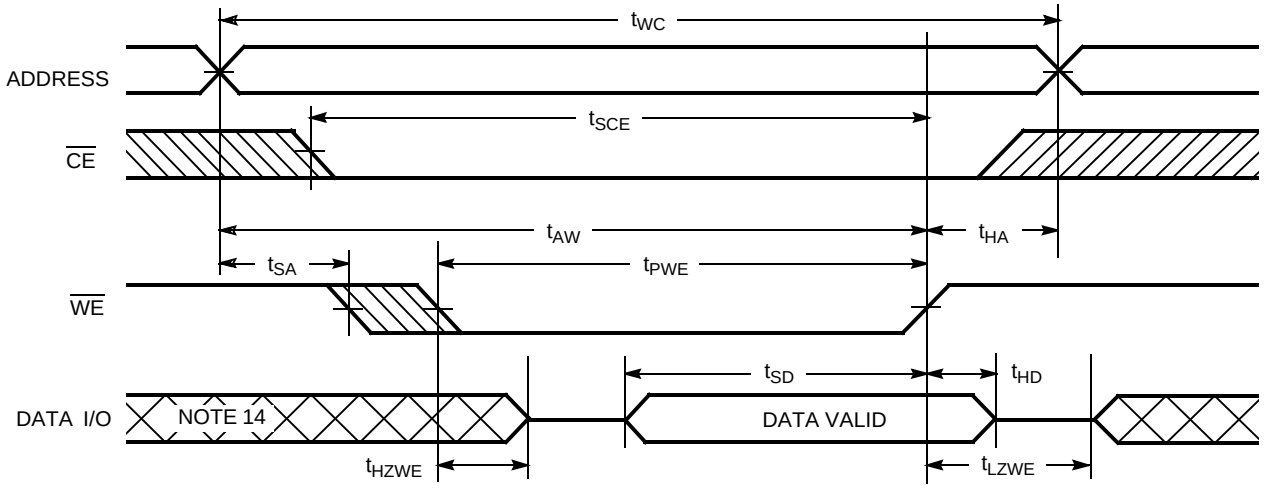

### Write Cycle No. 2 ($\overline{WE}$ Controlled, $\overline{OE}$ HIGH During Write)[12, 13]




**Notes:**
12. Data I/O is high impedance if $\overline{OE}$ = $V_{IH}$.
13. If $\overline{CE}$ goes HIGH simultaneously with $\overline{WE}$ going HIGH, the output remains in a high-impedance state.
14. During this period the I/Os are in the output state and input signals should not be applied.

## Switching Waveforms (continued)

**Write Cycle No. 3 ($\overline{WE}$ Controlled, $\overline{OE}$ LOW)**[13]




## Truth Table

| $\overline{CE}$ | $\overline{OE}$ | $\overline{WE}$ | $I/O_0$–$I/O_7$ | Mode | Power |
|---|---|---|---|---|---|
| H | X | X | High Z | Power-Down | Standby ($I_{SB}$) |
| L | L | H | Data Out | Read | Active ($I_{CC}$) |
| L | X | L | Data In | Write | Active ($I_{CC}$) |
| L | H | H | High Z | Selected, Outputs Disabled | Active ($I_{CC}$) |

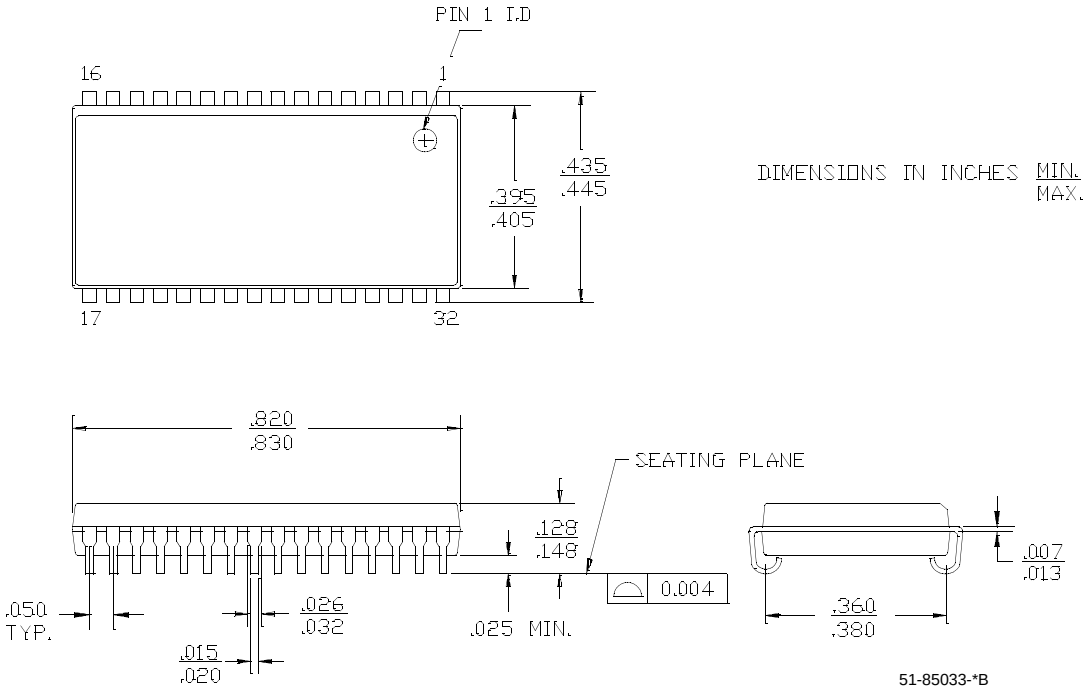
## Ordering Information

| Speed (ns) | Ordering Code | Package Name | Package Type | Operating Range |
|---|---|---|---|---|
| 12 | CY7C1019B-12VC | 51-85033 | 32-pin 400-Mil Molded SOJ | Commercial |
| | CY7C1019B-12ZC | 51-85095 | 32-pin TSOP Type II | |
| | CY7C1019B-12ZXC | | 32-pin TSOP Type II (Pb -Free) | |
| 15 | CY7C1019B-15VC | 51-85033 | 32-pin 400-Mil Molded SOJ | Commercial |
| | CY7C1019B-15ZXC | 51-85095 | 32-pin TSOP Type II (Pb -Free) | |

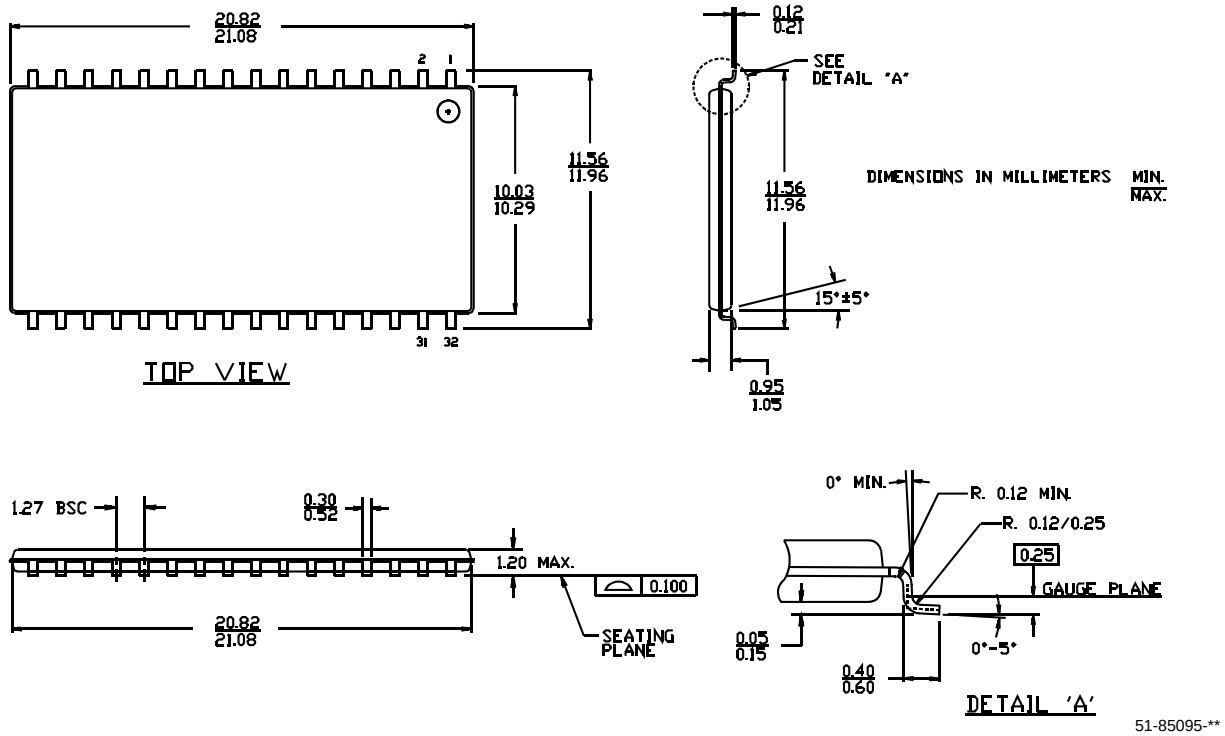
Please contact local sales representative regarding availability of these parts

## Package Diagrams

**32-pin (400-mil) Molded SOJ (51-85033)**




**32-pin TSOP II (51-85095)**



## Document History Page

| Document Title: CY7C1019B 128K x 8 Static RAM<br>Document Number: 38-05026 | | | | |
|---|---|---|---|---|
| **REV.** | **ECN NO.** | **Issue Date** | **Orig. of Change** | **Description of Change** |
| ** | 109949 | 09/25/01 | SZV | Change from Spec number: 38-01115 to 38-05026 |
| *A | 116170 | 08/14/02 | HGK | 1. SOJ (400-mil) package outline replacing incorrect SOJ package<br>2. Pin for pin compatible with CY7C1019<br>3. Industrial packages added to Ordering Information |
| *B | 397875 | See ECN | NXR | Changed address of Cypress Semiconductor Corporation on Page# 1 from “3901 North First Street” to “198 Champion Court”<br>Updated the Ordering Information Table on page # 6 |
| *C | 493543 | See ECN | NXR | Removed CY7C10191B from product offering<br>Removed Industrial Operating Range<br>Changed the description of $I_{IX}$ from Input Load Current to Input Leakage Current in DC Electrical Characteristics table<br>Removed $I_{OS}$ parameter from DC Electrical Characteristics table<br>Updated Ordering Information table |